



New Applications of Deep Learning in Health Monitoring Systems

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Message from the Guest Editor

With a massive influx of multimodality data, data analytics play an increasingly important role in health informatics in the last decade. This also prompts rapidly growing research in the analytical method and data-driven models based on machine learning in health informatics. Deep learning, a technique with its foundation in artificial neural networks, is emerging in recent years as a powerful tool for machine learning. Considering the capability of addressing large-scale data and learning multi-scale/multi-level/hierarchical representation, deep learning can be a powerful and effective solution for health monitoring systems. Therefore, this Special Issue aims to present researchers and engineers with a global view of this hot and active topic on novel deep learning-based health monitoring system applications.

Subjects that will be discussed in this Special Issue will focus not only on modern methods and data-driven approaches based on deep learning, but also on the applications and their properties in health monitoring systems.





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Message from the Editor-in-Chief

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